MSKSEMI 美森科













ESD

TVS

TSS

MOV

GDT

PIFD

AO4409-MS

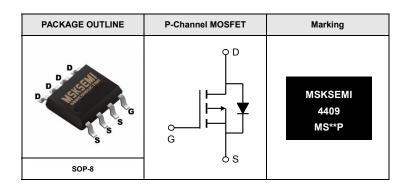
Product specification





Features

- V_{DS} (V) = -30V
- ID = -15A (Vgs = 10V)
- RDS(ON) < 7.50m Ω (VGS = -10V)
- RDS(ON) $< 12m\Omega$ (VGS = -4.5V)



Absolute Maximum Ratings (T_A=25℃unless otherwise noted)

Parameter		Symbol	Rating	Unit
Drain-Source Voltage		VDS	-30	
Gate-Source Voltage		Vgs	±20	V
	TA=25°C	lo	-15	
Continuous Drain Current	TA=70°C		-12.8	
Pulsed Drain Current		lом	-80	A
Avalanche Current		las,lar	30	
Avalanche energy	L=0.1mH	Eas,Ear	135	mJ
	TA=25°C		3.1	
Power Dissipation	TA=70°C	Pb	2	W
	t ≤ 10s		40	
Thermal Resistance.Junction- to-Ambient	Steady-State	RthJA	75	°C/W
Thermal Resistance.Junction- to-Lead		RthJL	24	3,11
Junction Temperature		TJ	150	
Junction Storage Temperature Range		Tstg	-55 to 150	$^{\circ}\mathbb{C}$



Electrical Characteristics Ta = 25° C

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
Drain-Source Breakdown Voltage	VDSS	ID=-250 μA, VGS=0V	-30			٧
		V _{DS} =-30V, V _{GS} =0V			-5	
Zero Gate Voltage Drain Current	IDSS	VDS=-30V, VGS=0V, TJ=55°C			-25	uA
Gate-Body leakage current	Igss	VDS=0V, VGS= ±20V			±100	nA
Gate Threshold Voltage	VGS(th)	VDS=VGS ID=-250 µA	-1.4		-2.7	V
		Vgs=-10V, ID=-15A			7.5	
Static Drain-Source On-Resistance	RDS(On)	Vgs=-10V, ID=-15A TJ=125℃			11.5	
		VGS=-4.5V, ID=-10A			12	mΩ
On state drain current	ID(ON)	Vgs=-10V, Vps=-5V	-80			Α
Forward Transconductance	gFS	VDS=-5V, ID=-15A	35	50		S
Input Capacitance	Ciss			5270	6400	
Output Capacitance	Coss	Vgs=0V, Vds=-15V, f=1MHz		945		_
Reverse Transfer Capacitance	Crss			745		pF
Gate resistance	Rg	Vgs=0V, Vds=0V, f=1MHz		2	3	Ω
Total Gate Charge (10V)				100	120	
Total Gate Charge (4.5V)	Qg	\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\		51.5		
Gate Source Charge	Qgs	VGS=-10V, VDS=-15V, ID=-15A		14.5		nC
Gate Drain Charge	Qgd			23		
Turn-On DelayTime	t d(on)			14		
Turn-On Rise Time	tr	Vgs=-10V, Vps=-15V,		16.5		
Turn-Off DelayTime	t d(off)	RL=1 Ω , RGEN=3 Ω		76.5		
Turn-Off Fall Time	tf			37.5		ns
Body Diode Reverse Recovery Time	trr			36.7	45	
Body Diode Reverse Recovery Charge	Qrr	IF=-15A, di/dt=100A/us		28		nC
Maximum Body-Diode Continuous Current	ls				-5	Α
Diode Forward Voltage	VsD	Is=-1A,VGS=0V			-1	V

Note : The static characteristics in Figures 1 to 6 are obtained using <300 μs pulses, duty cycle 0.5% max.



Typical Characterisitics

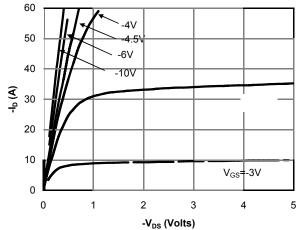
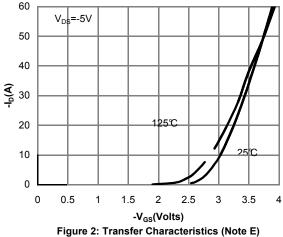


Fig 1: On-Region Characteristics (Note E)



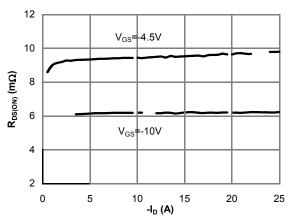


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

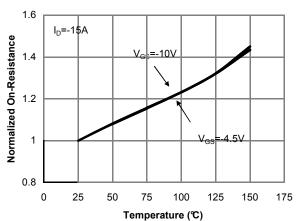


Figure 4: On-Resistance vs. Junction Temperature (Note E)

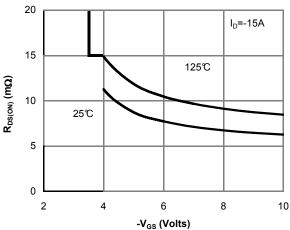


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

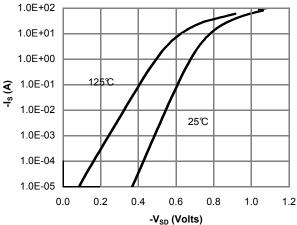


Figure 6: Body-Diode Characteristics (Note E)



Typical Characterisitics

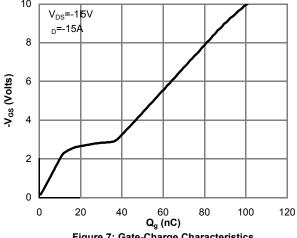


Figure 7: Gate-Charge Characteristics

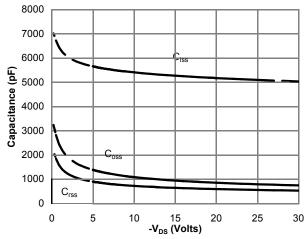


Figure 8: Capacitance Characteristics

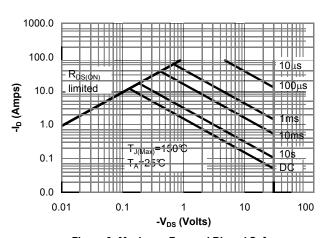


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

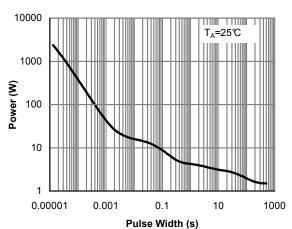


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

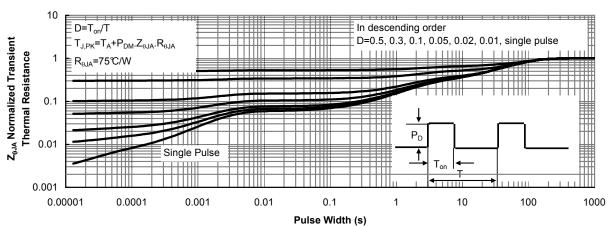
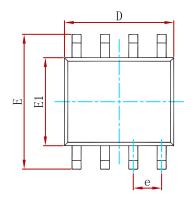
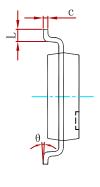


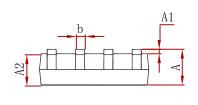
Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)



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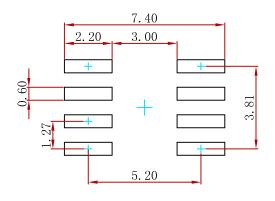






Cumbal	DimensionsIr	Millimeters	Dimension	nsInInches	
Symbol	Min	Max	Min	Max	
A	1.350	1. 750	0.053	0.069	
A1	0.100	0. 250	0.004	0.010	
A2	1.350	1.550	0.053	0.061	
b	0.330	0. 510	0.013	0.020	
с	0.170	0.250	0.007	0.010	
D	4.800	5.000	0.189	0.197	
e	1.270 (BSC)		0.050 (BSC)		
Е	5.800	6. 200	0. 228	0.244	
E1	3.800	4.000	0.150	0.157	
L	0.400	1. 270	0.016	0.050	
θ	0°	8°	0°	8°	

Suggested Pad Layout



- 1.Controlling dimension:in millimeters. 2.General tolerance:± 0.05mm.
- 3. The pad layout is for reference purposes only.

REELSPECIFICATION

P/N	PKG	QTY
AO4409-MS	SOP-8	3000



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